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 Patent and Trademark Office

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	280250	P-0181.010
Applicant: van der Schaar et al. <i>#4</i>		
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Examiner: Unassigned		Group Art Unit: Applications Branch

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**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

Date: April 26, 2001

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**U.S. PATENT DOCUMENTS**

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AR						
BR						
CR						
DR						
ER						
FR						
GR						
HR						
IR						
JR						
KR						
LR						
MR						
NR						

**FOREIGN PATENT DOCUMENTS**

	Document Number	Date MM/YYYY	Country	Inventor Name		English Abstract	Translation Readily Available		
						Enclosed	No	Enclose	No
OR									
PR									
QR									
RR									
SR									
TR									
UR									

**OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)**

<i>DBE</i>	VR	J.A. Rogers et al., "A New Photoacoustic/Photothermal Device for Real-Time Materials Evaluation: An Automated means for Performing Transient Grating Experiments", PHYSICA B Vols. 219 & 220 (1996), pp 562-564	
<i>DBE</i>	WR	Lisa Dhar et al., "Moduli Determination in Polyimide Film Bilayer Systems: Prospects for Depth Profiling Using Impulsive Stimulated Thermal Scattering", J. APPLIED PHYSICS Vol. 77, No. 9, May 1, 1995, pp 4431-4444	
<i>DBE</i>	XR	R. Logan et al., "Microelectronic Film Thickness Determination Using a Laser-Based Ultrasonic Technique", MATERIALS RESEARCH SOCIETY SYMPOSIUM PROC. Vol 440, Vol. 1997	

Examiner *D. Beringer* Date Considered: *4/16/03*

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.